Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/719,758	LEE ET AL.	
Examiner	Art Unit	
David Buttner	1712	

	SEARCHED		
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			

SEAR (INCLUDING SE	CH NOTES EARCH STRATEG	Y)
	DATE	EXMR
inventor search	5/1/2006	DB
chem ab	5/1/2006	DB
east	5/1/2006	DB